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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 09/833,084

Confirmation No.: 8866

First Named Inventor: Ibrahim Abdulhalim et al.

Filing Date: April 10, 2001

Group Art Unit: 1775

Examiner: Unknown

Atty. Docket No.: TNCR.196US0

Title: PERIODIC PATTERNS AND TECHNIQUE TO CONTROL  
MISALIGNMENT

Assignee: KLA-TENCOR CORPORATION

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GROUP 1700

San Francisco, California  
March 27, 2003

COMMISSIONER FOR PATENTS  
Washington, D. C. 20231

**SUPPLEMENTAL  
INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97, and 1.98, Applicants call the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

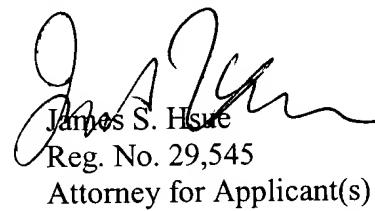
Copies of the documents listed on the accompanying Form PTO-1449 are enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required.

**EXPRESS MAIL LABEL NO.:**  
**EV 111851338 US**

Respectfully submitted,

  
James S. Hsue  
Reg. No. 29,545  
Attorney for Applicant(s)

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U.S. Department of Commerce, Patent and Trademark Office		Atty Docket No.	Application No.
		TNCR.196US0	09/833,084
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Applicant(s)	Confirmation No.
(Use several sheets if necessary)		Ibrahim Abdulhalim, et al.	8866
		Filing Date	Group
		April 10, 2001	1775

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## U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,200,395	04/29/80	Smith et al.	356	356	
	AB	4,332,473	01/05/82	Ono	356	356	
	AD	4,757,207	07/12/88	Chappelow et al.	250	491.1	
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	AI						
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	AD						
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	AG						
	AK						
	AD						
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	AG						
	AH						
	AI						

## Foreign Patent Documents

						Translation		
		Document	Date	Country	Class	Subclass	Yes	No
	AL	WO 01/73824 A1	10/04/01	PCT				
	AM							

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AQ	R. Pforr, et al., "In-Process Image Detecting Technique For Determination Of Overlay, And Image Quality For ASM-L Wafer Stepper", SPIE Vol. 1674 Optical/Laser Microlithography V (1992) pp. 594-608
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Examiner	Date Considered
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.